



TFl

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Marc RABAROT et al.

Group Art Unit: 1794

Application No.: 10/538,351

Examiner: M. JACKSON

Filed: June 10, 2005

Docket No.: 124253

For: MICROSTRUCTURE COMPRISING AN ADHESIVE LAYER AND METHOD OF FABRICATION OF SAID MICROSTRUCTURE

APPLICANTS' SEPARATE RECORD OF PERSONAL INTERVIEW

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The courtesies extended to Applicant's representative by Examiner Jackson at the interview held December 2, 2008, are appreciated. The reasons presented at the interview as warranting favorable action are incorporated into the remarks below and constitute Applicant's record of the interview.

During the interview, the recently submitted amendments and arguments were discussed. In addition, the Examiner acknowledged that Miyagawa does not disclose the thickness of the layers recited in claim 12.

Should the Examiner have any questions or comments, the Examiner is invited to contact the undersigned at the telephone number set below.

Respectfully submitted,



James A. Oliff
Registration No. 27,075

Benjamin S. Prebyl
Registration No. 60,256

JAO:BSP

Date: December 4, 2008

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461
--